



BNERC @ Toyo Univ. – JEOL Ltd. Joint workshop

WED 23rd MAY. 2018

Time	Event
13:00	Arrival at the JEOL Ltd.
	Welcome address <i>Mr. Iwatsuki</i>
13:15	Outline of the project <i>Dr Chris Ewels</i>
13:30 –	JEOL presentation 1: TEM <i>Latest application at atomic level by using aberration corrected electron microscope</i> <i>Dr. Eiji OKUNISHI</i>
14:00 –	JEOL presentation 2: SEM <i>Ultra High Resolution FE-SEM analysis in material science</i> <i>Mr. Yasuaki YAMAMOTO</i>
14:30 –	Coffee Break
14:45 –	JEOL presentation 3: 3D in SEM <i>3D observation by using SEM</i> <i>Dr. Mitsuo SUGA</i>
15:15 –	Functional demo @ the instruments. Table below.
16: 15-	Closing address <i>Dr. MAEKAWA (BNERC)/Mr. OKAYAMA (JEOL)</i>

Time	Group A	Group B	Group C
15:15-	TEM	3D in SEM	SEM
15:35-	SEM	TEM	3D in SEM
15:55-	3D in SEM	SEM	TEM

TEM: JEM-F200(CF-HR) in B1

SEM: JSM-7900F and JSM-7200F in B1

3D in SEM: Array Tomography/CLEM in 1F